Abstracts

An Automated General Purpose Test System for Solid State L.O.'s (Abstract)

J.R. Humphrey. "An Automated General Purpose Test System for Solid State L.O.'s (Abstract)." 1974 S-MTT International Microwave Symposium Digest of Technical Papers 74.1 (1974 [MWSYM]): 268-268.

Automation has provided a cost-effective solution to test problems associated with solid-state local oscillators. Computer controlled measurement and analysis for L.O.'s, L-Band through Ku-Band, is provided by a single system. Improved testing provides positive feedback to design efforts and enhances device tuning capability.

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